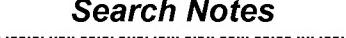


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/584,003	NIFANT'EV ET AL.	
	<b>Examiner</b> RIP A. LEE	<b>Art Unit</b> 1796	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
526	172	3/31/2009	RL
526	161	3/31/2009	RL
556	53	3/31/2009	RL